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| No. | Test item | Conditions | Conditions of acceptability | Result |
|-----|---|--|---|--------|
| 1 | High temp./overload test | (1) Input : Max.voltage, Min.voltage (2) Output : Overload (3) Case top temp. : 5 Vin, 105°C 24/48 Vin, 110°C (4) Test period : 48 hours | (1)Power supply is not failed. | ok |
| 2 | High voltage input test | (1) Input : 2 times of rated voltage (2) Output : Rated output (3) Ambient temp. : 25±10°C | (1)No smoke, no fire. | ok |
| 3 | Low voltage input test | (1) Input : Min. regulation voltage (2) Output : Rated output (3) Ambient temp. : 25±10°C (4) Test period : 48 hours | (1)Power supply is not failed. | ok |
| 4 | Input ON/OFF test | (1) Input : Max.voltage T= 2sec Duty= 50% (2) Output : Rated output (3) Ambient temp. : 60±10°C (4) ON/OFF period : 1,000 | (1)Power supply is not failed. (2)The surge current of each components should not exceed the rated value. | ok |
| 5 | Output ON/OFF test | (1) Input : Rated input (2) Output : 0%↔100% T= 2sec Duty= 50% (3) Ambient temp. : 25±10°C (4) ON/OFF period : 1,000 | (1)Power supply is not failed. | ok |
| 6 | Output-short start test | (1) Input : Rated input (2) Output : Short start (3) Ambient temp. : 25±10°C | (1)Power supply is not failed. | ok |
| 7 | Output short test | (1) Input : Rated input (2) Output : Short (3) Ambient temp. : 25±10°C (4) Test period : 48 hours | (1)Power supply is not failed. | ok |
| 8 | Withstand voltage test (High-pot test) | (1) Input : N/A (2) Ambient temp. : 25±10°C (3)Test voltage : 1.4 times of specifications. | (1)Insulation breakdown , flashover or electric arc is not occurred | ok |
| 9 | Isolation resistance test | (1) Input : N/A (2) Ambient temp. : 25±10°C | (1)When a regulation voltage is applied, isolation resistance is 1.4 times of specifications. | ok |
| 10 | Vibration/impact test | Vibration (1)f=10~55Hz : 98.0m/s ² (2)3 minutes period (3)60 minutes along X, Y and Z axis Impact (1)490.3m/s ² 11ms (2)Once each X, Y and Z axis | (1)No degradation of electric characteristics after test. (2)No crack at solder joint. (3)No marked damage of appearance. | ok |